

Application/Control No.	Applicant(s)/Patent under Reexamination CHAIKEN ET AL.	
Eric Chang	2116	_

	SEARCHED					
Class	Subclass	Date	Examiner			
	-					

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
L						

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
,	DATE	EXMR	
EAST USPAT/PGPUB EPO/JPO	3/5/2007	EC	